

# Effect of substrate porosity and doping concentration on the thermochromic properties VO<sub>2</sub>

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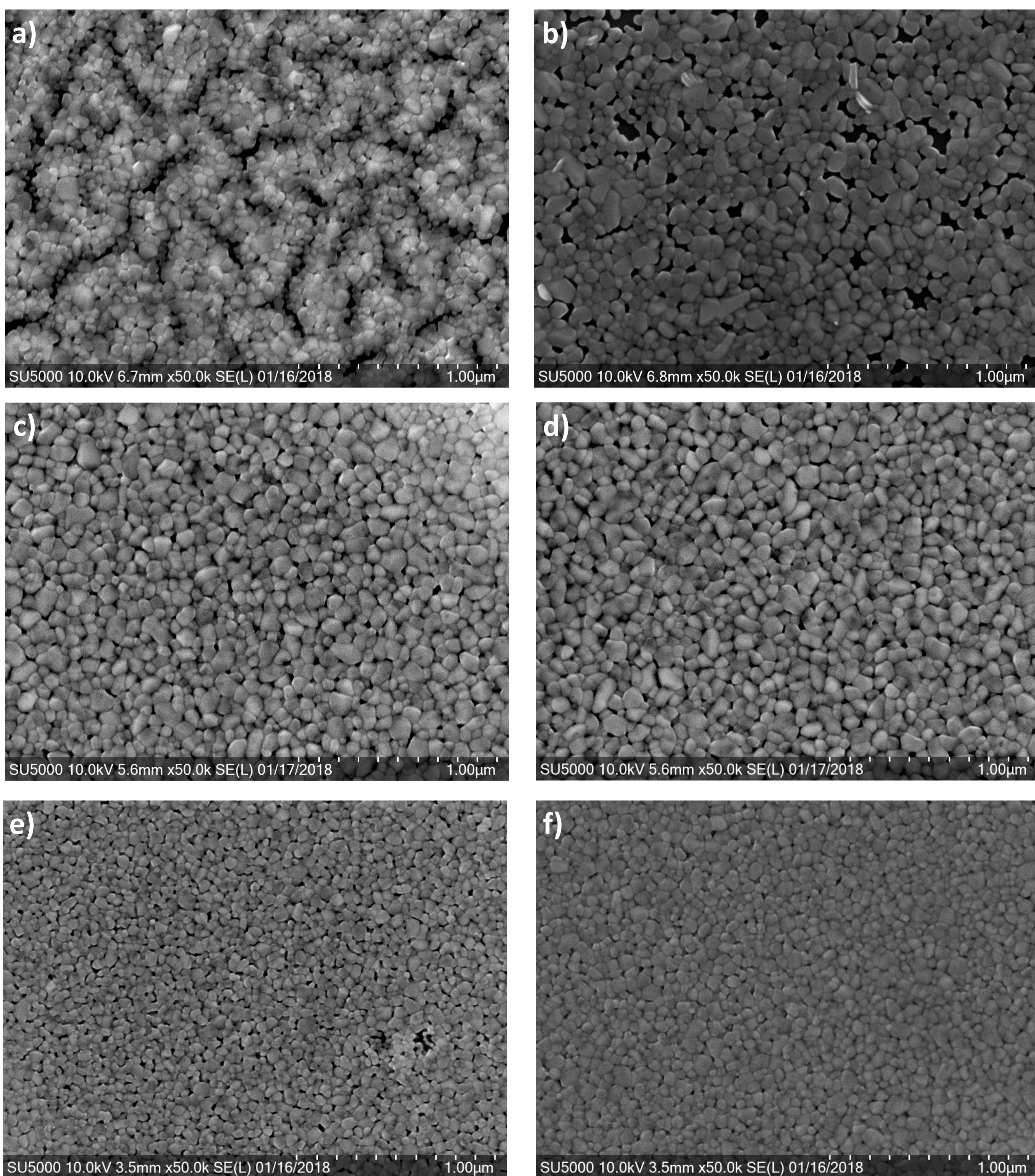
## Abstract

VO<sub>2</sub> has a semiconductor-metal reversible transition (SMT) phase at T<sub>c</sub>=68°C, which has been used for several applications [1-2]. In this work, the changes in the VO<sub>2</sub> transition temperature are studied as a function of doping concentration of TiO<sub>2</sub> nanoparticles (1 and 4% of TiO<sub>2</sub>). The optical response of the composite sample formed over porous silicon (PSi) substrate was measured as a function of temperature with respect to the control sample over crystalline (cSi) substrate.

## Preparation of VO<sub>2</sub>/PSi structure

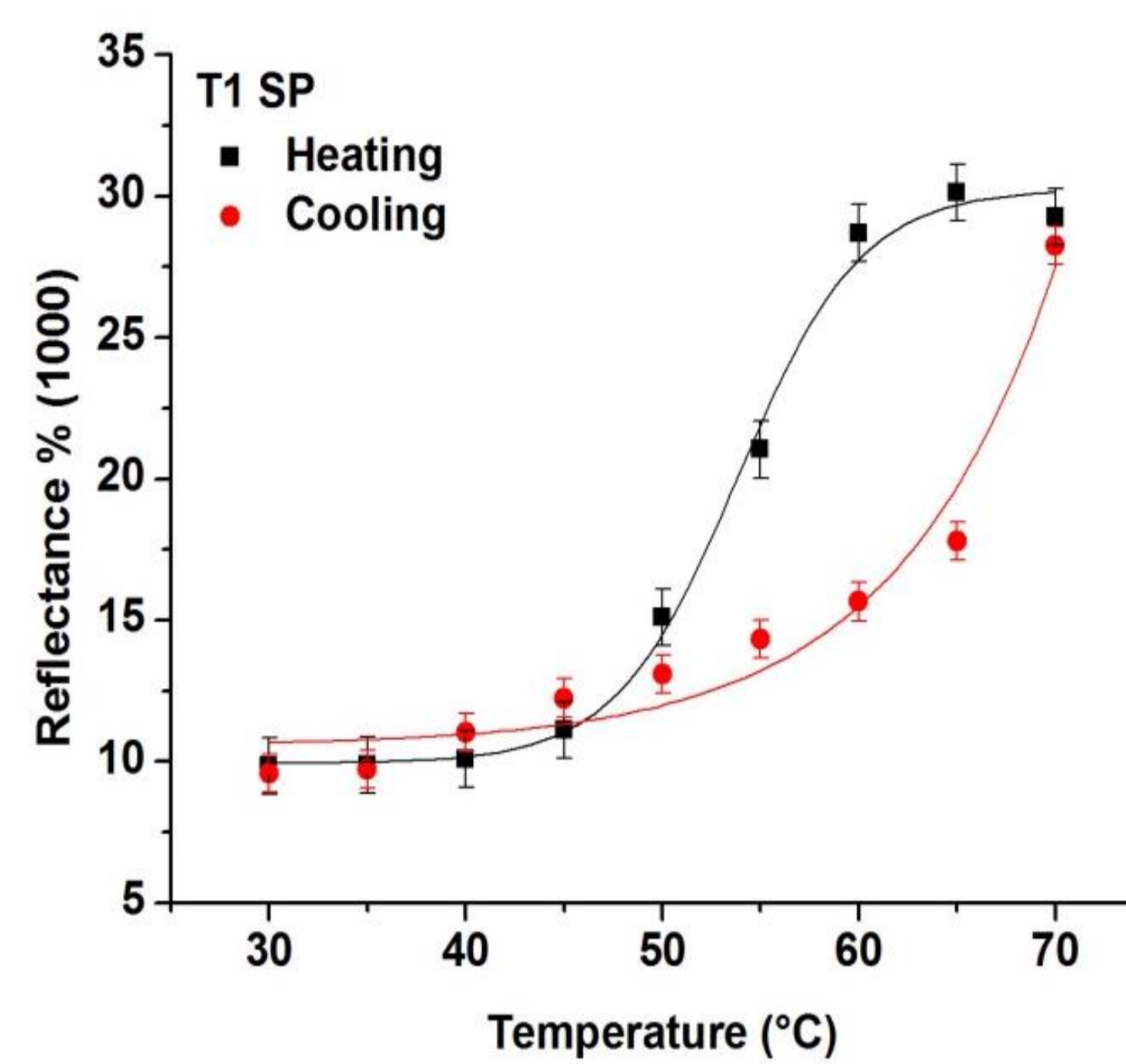
PSi layer was prepared by anodic dissolution applying the current density of 55 mA/cm<sup>2</sup> for 10 s on electrolyte mixture of aqueous HF, ethanol, and glycerol, in 3:7:1 proportion of volume, respectively. The VO<sub>2</sub> was spin coated (2500 rpm for 60 s) onto the PSi matrix followed by annealing under nitrogen atmosphere at 450°C for 60 min [3].

## Results

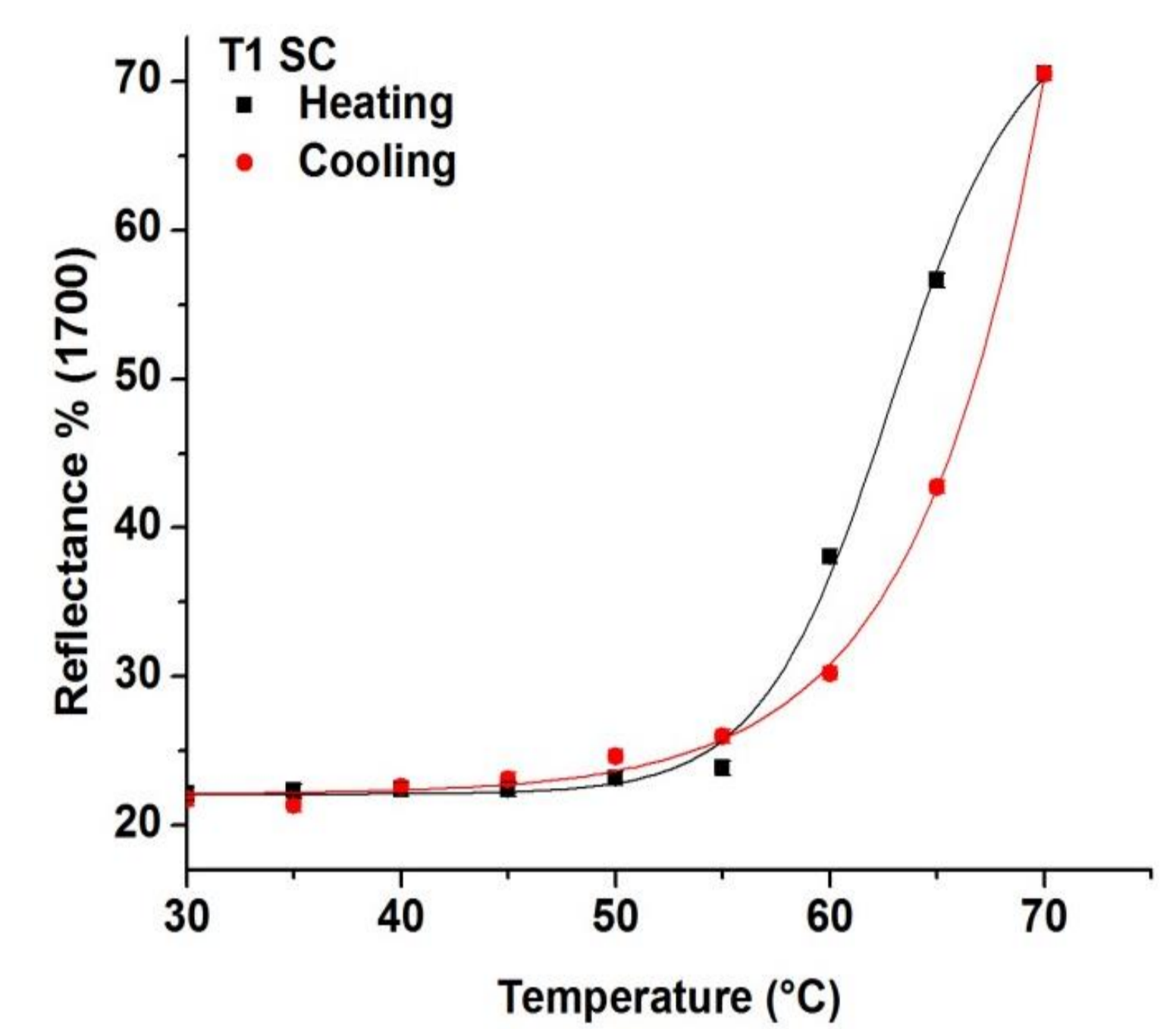


**Figura 1.** SEM images of undoped VO<sub>2</sub> film on (a) PSi, (b) cSi and (c) doped VO<sub>2</sub> films with 1% TiO<sub>2</sub>/PSi, (d) 1% TiO<sub>2</sub>/cSi, (e) 4% TiO<sub>2</sub>/PSi, (f) 4% TiO<sub>2</sub>/cSi.

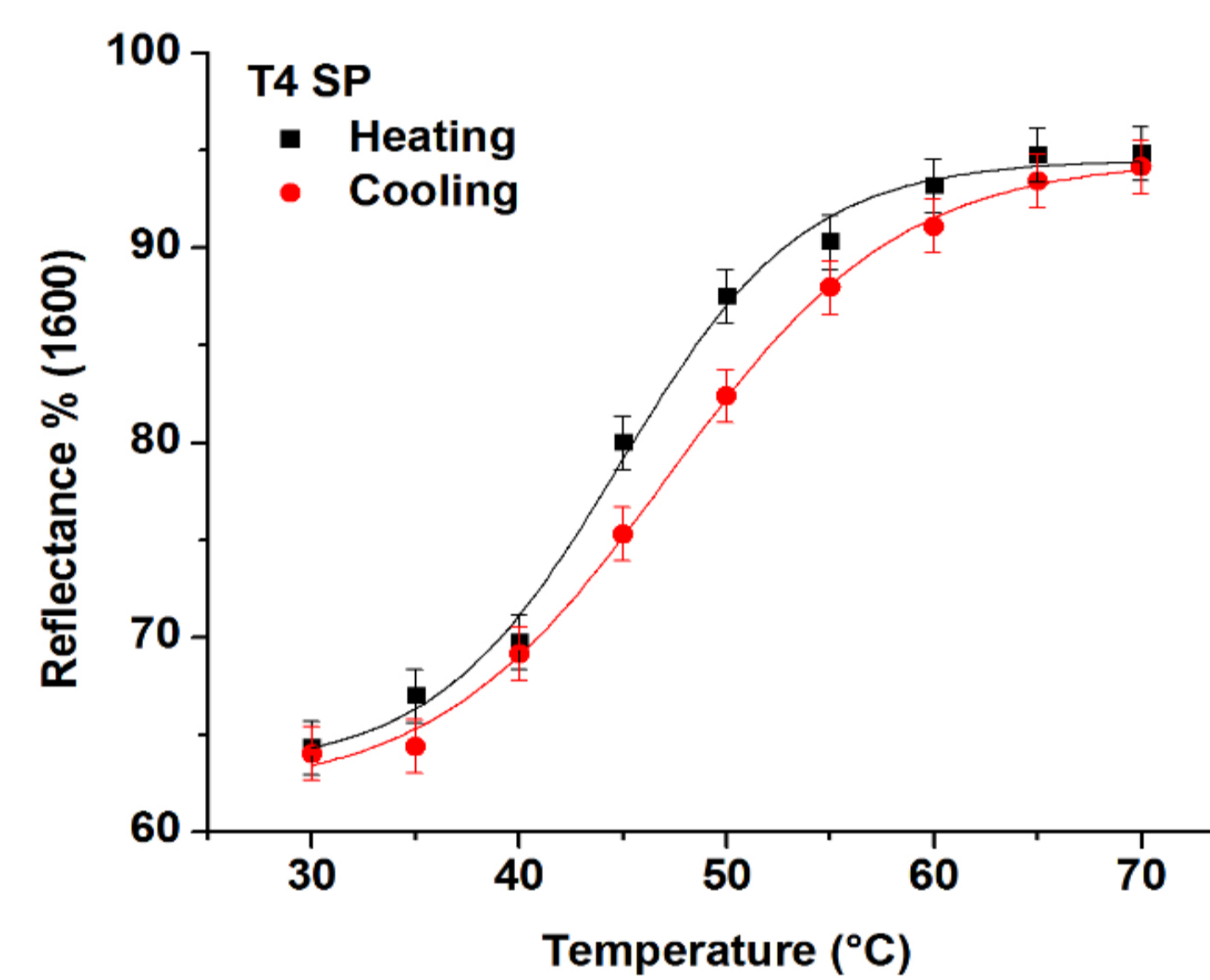
## Optical Characterization



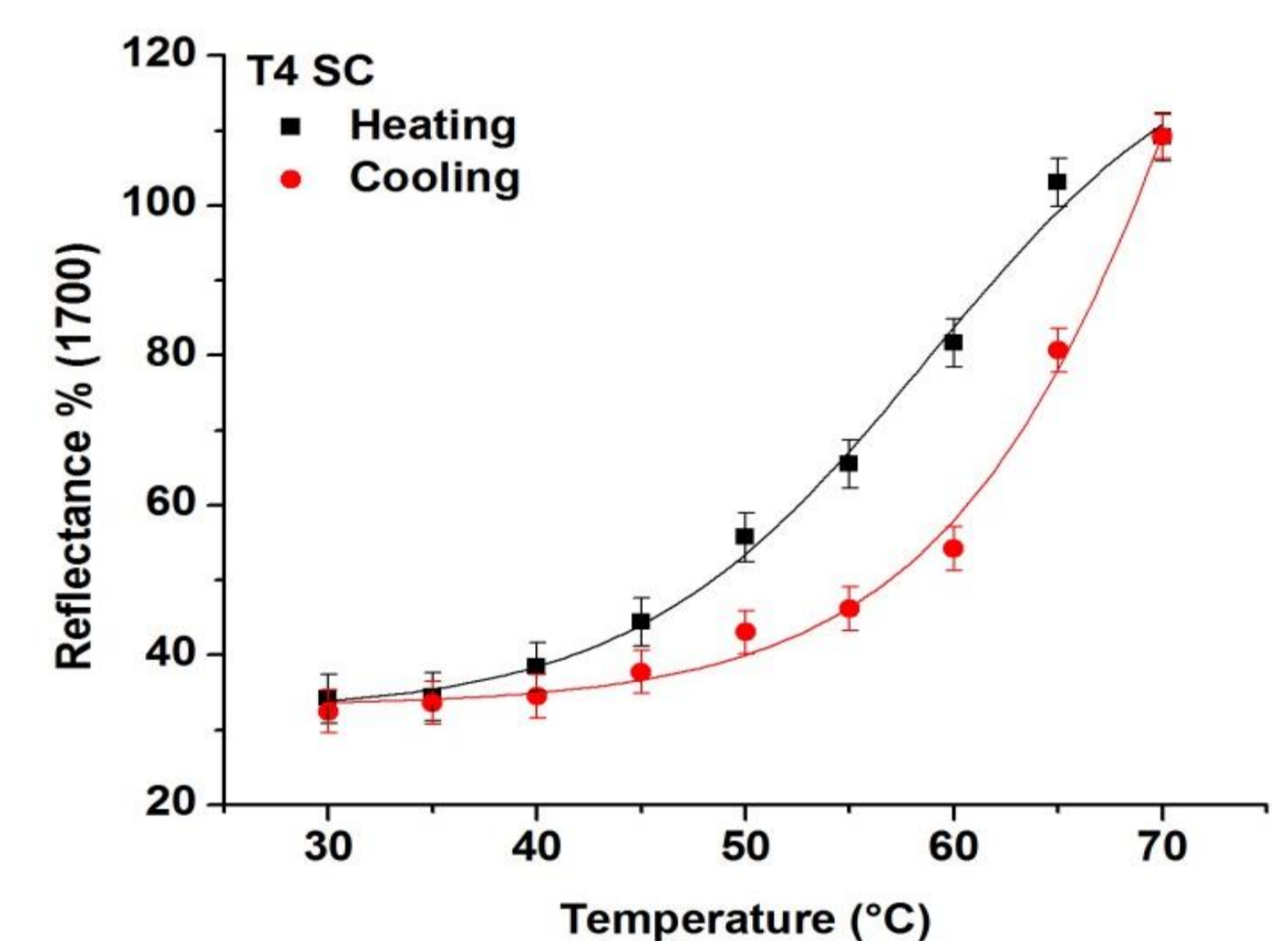
**a)** 1% TiO<sub>2</sub>/PSi T<sub>c</sub>=60.2°C



**b)** 1% TiO<sub>2</sub>/cSi T<sub>c</sub>=64.5°C



**c)** 4 % TiO<sub>2</sub>/PSi T<sub>c</sub>=50.6°C



**d)** 4 % TiO<sub>2</sub>/cSi T<sub>c</sub>=60.5°C

**Figura 2.** Hysteresis curve : Reflectance of doped VO<sub>2</sub> films measured at a particular wavelength as a function of temperature.

## Conclusions

- An increase in the doping concentration results in the formation of densely packed and more homogeneous films with smaller grain size. This decrease in the grain size has been attributed to the enhanced defect-nucleation site density introduced by doping.
- An increase in TiO<sub>2</sub> concentration, SMT transition temperature of VO<sub>2</sub> films was decreased with an additional increase in surface porosity.
- Contrary to the VO<sub>2</sub> films deposited on the cSi substrate, hysteresis loop width is found to decrease for the films deposited over PSi substrates. Attributed to the porous morphology provoking the mechanical clamping and hence contributing to the decrease in the SMT transition temperature.

## References

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2. H.Kakiuchida, P.Jin, M.Tazawa, Optical characterization of vanadium- titanium oxide films, Thin Solid Films 516(2008)4563–4567.
3. E. E. Antunez, U. Salazar-Kuri, J. O. Estevez1, J. Campos, M. A. Basurto, S. Jiménez Sandoval, and V. Agarwal. Porous silicon-VO<sub>2</sub> based hybrids as possible optical temperature sensor: Wavelength-dependent optical switching from visible to near-infrared range. Journal of Applied Physics 118, 134503 (2015); <https://doi.org/10.1063/1.4932023>